

VBJ1695 Datasheet N-Channel 60-V (D-S) MOSFET

PRODUC	CT SUMMARY		
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^a	Q _g (Typ.)
<u></u>	0.076 at V _{GS} = 10 V	4.5	10 nC
60	0.085 at V _{GS} = 4.5 V	3.5	TUTIC

FEATURES

• Halogen-free

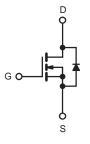
APPLICATIONS

• TrenchFET[®] Power MOSFET

· Load Switches for Portable Devices



SOT-223-3



N-Channel MOSFET

ABSOLUTE MAXIMUM RATIN	IGS T _A = 25 °C,	unless othe	rwise noted	
Parameter		Symbol	Limit	Unit
Drain-Source Voltage		V _{DS}	60	V
Gate-Source Voltage		V _{GS}	± 20	V
	T _C = 25 °C		4.5	
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C		3.2 ^a	
	T _A = 25 °C		2.7	
	T _A = 70 °C	1	2.3	A
Pulsed Drain Current		I _{DM}	20	
Continuous Source-Drain Diode Current	T _C = 25 °C	I _S	3.2	
Continuous Source-Drain Diode Current	T _A = 25 °C	'5	2.1 ^{b, c}	
	T _C = 25 °C		4.0	
Maximum Power Dissipation	T _C = 70 °C	P _D	3.0	w
	T _A = 25 °C		2.5 ^{b, c}	
	T _A = 70 °C		1.6 ^{b, c}	
Operating Junction and Storage Temperatur	e Range	T _J , T _{stg}	- 55 to 150	°C
Soldering Recommendations (Peak Temper	ature) ^{e, f}		260	Ū

THERMAL RESISTANCE BATINGS

Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient ^{a, c, d} $t \le 5 s$		R _{thJA}	40	50	°C/W		
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	15	20	0/11		

Notes:

a. Package limited, T_C = 25 °C.
b. Surface Mounted on 1" x 1" FR4 board.

c. t = 10 s.

d. Maximum under Steady State conditions is 95 °C/W.

e. See Reliability Manual for profile. The ChipFET is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.

f. Rework Conditions: manual soldering with a soldering iron is not recommended for leadless components.

SPECIFICATIONS $T_J = 25 \ ^{\circ}C$,			-				
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static			r	r	T	T	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_{D} = 250 \mu A$	60			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		25			
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	_ ·		- 4.0		mV/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	1.0		2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 12 V$			± 100	nA	
Zero Gate Voltage Drain Current	la a a	$V_{DS} = 60 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			1		
Zero Gale voltage Drain Current	IDSS	V_{DS} = 60 V, V_{GS} = 0 V, T_{J} = 55 °C			10	μA	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \geq 5$ V, V_{GS} = 4.5 V	30			Α	
	D	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 4.0 \text{ A}$		0.076			
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 V, I_{D} = 3.0 A$		0.085		Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = 10 V, I _D = 4.0 A		45		S	
Dynamic ^b					•	•	
Input Capacitance	C _{iss}			810		pF	
Output Capacitance	C _{oss}	$V_{DS} = 30V$, $V_{GS} = 0$ V, f = 1 MHz		120			
Reverse Transfer Capacitance	C _{rss}		-	100			
		$V_{DS} = 30$ V, $V_{GS} = 10$ V, $I_{D} = 4.0$ A		22	33		
Total Gate Charge	Qg			10	15	nC	
Gate-Source Charge	Q _{gs}	V_{DS} = 30 V, V_{GS} = 4.5 V, I_{D} = 3.0 A		2.5			
Gate-Drain Charge	Q _{gd}			1.7			
Gate Resistance	R _g	f = 1 MHz		2.4		Ω	
Turn-on Delay Time	t _{d(on)}			15	25		
Rise Time	t _r	V _{DD} =30V, , R _I = 1.5 Ω		10	15	- - - ns	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 4.0 \text{ A}, \text{ V}_{\text{GEN}} = 4.5 \text{ V}, \text{ R}_{\text{g}} = 1 \Omega$		35	55		
Fall Time	t _f	-		12	20		
Turn-on Delay Time	t _{d(on)}			10	15		
Rise Time	t _r	$V_{DD} = 30V, R_1 = 1.5 \Omega$		12	20		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 4.0 \text{ A}, V_{GEN} = 10 \text{ V}, \text{ R}_{g} = 1 \Omega$		25	40		
Fall Time	t _f			10	15		
Drain-Source Body Diode Characteristic	-						
Continuous Source-Drain Diode Current	۱ _S	T _C = 25 °C			7.2	1	
Pulse Diode Forward Current	I _{SM}				30	A	
Body Diode Voltage	V _{SD}	I _S = 4.0 A, V _{GS} = 0 V		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			20	40	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			10	20	nC	
Reverse Recovery Fall Time	ta	$I_F = 4.0 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, \text{ T}_J = 25 ^\circ\text{C}$	<u> </u>	10			
Reverse Recovery Rise Time tb					I	ns	

Notes:

a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %

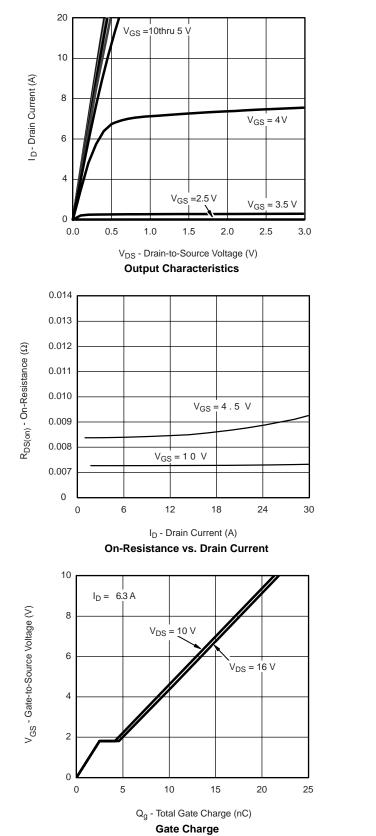
b. Guaranteed by design, not subject to production testing.

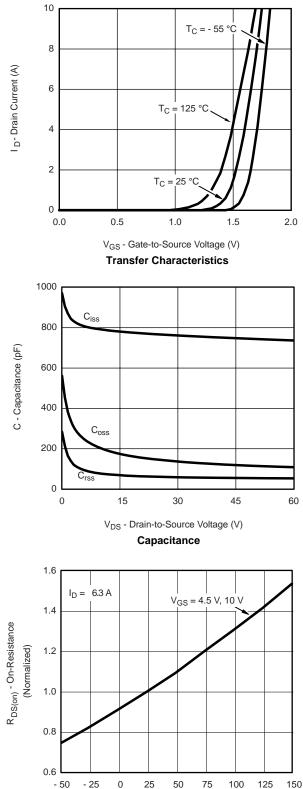
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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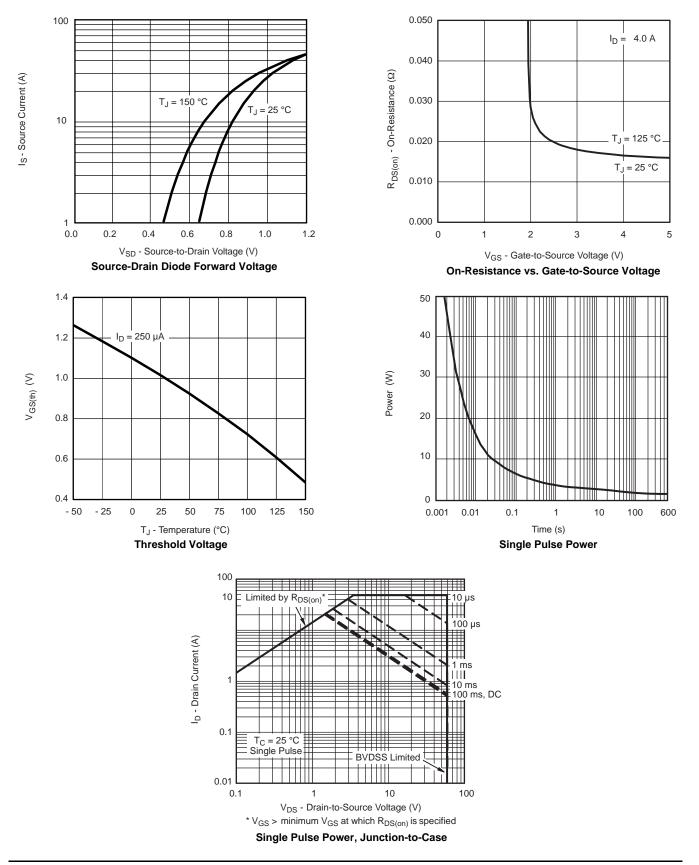




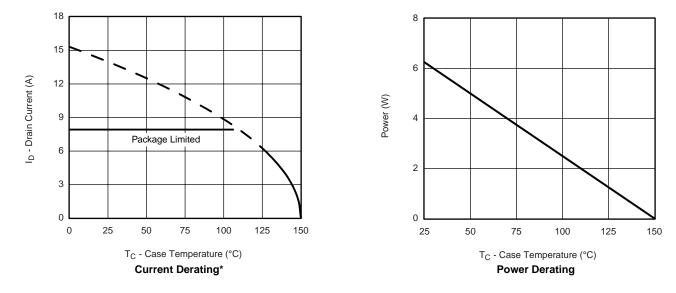
 T_J - Junction Temperature (°C)

On-Resistance vs. Junction Temperature



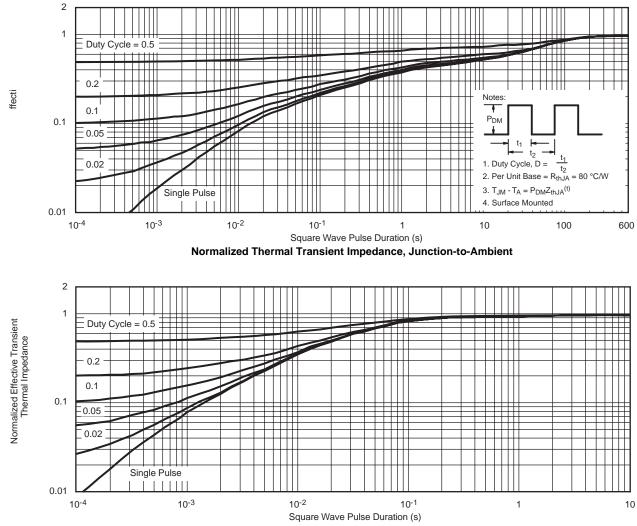






* The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

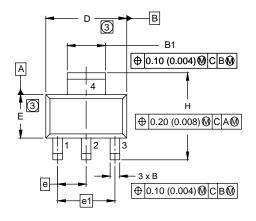


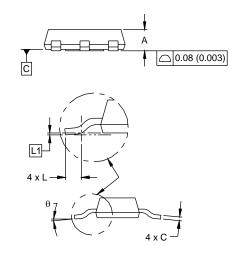


Normalized Thermal Transient Impedance, Junction-to-Foot



SOT-223 (HIGH VOLTAGE)





DIM.	MILLI	MILLIMETERS		INCHES		
	MIN.	MAX.	MIN.	MAX.		
А	1.55	1.80	0.061	0.071		
В	0.65	0.85	0.026	0.033		
B1	2.95	3.15	0.116	0.124		
С	0.25	0.35	0.010	0.014		
D	6.30	6.70	0.248	0.264		
E	3.30	3.70	0.130	0.146		
е	2.30 BSC		0.0905 BSC			
e1	4.60 BSC		0.181 BSC			
Н	6.71	7.29	0.264	0.287		
L	0.91	-	0.036	-		
L1	0.061 BSC		0.0024	4 BSC		
θ	-	10'	-	10'		

Notes

1. Dimensioning and tolerancing per ASME Y14.5M-1994.

2. Dimensions are shown in millimeters (inches).

3. Dimension do not include mold flash.

4. Outline conforms to JEDEC outline TO-261AA.



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